**Form PTO-1449** artment of Commerce Atty Docket 0756-2093 Serial No. 09/499,619 (Rev. 8-83) and Trademark Office Applicants: Shunpei YAMAZAKI INFORMATION DISCLOSURE STATEMENT Filing Date: February 07, 2000 Group Art Unit: 2815 **U.S. PATENT DOCUMENTS** Exampler Initial **Document Number** Date Name Class Subclass Filing Date (if appropriate) REUSCHEL.K 4,068,020 01/10/1978 4,103,297 07/25/1978 MCGREIVY et al. 4,239,346 12/16/1980 LLOYD.R 12/14/1982 BRODSKY et al. 4,363,828 4,365,013 12/21/1982 ISHIOKA et al. MARUYAMA et al. 4,378,417 03/29/1983 07/26/1983 MAEGUCHI.K 4,395,726 4,460,670 07/17/1984 OGAWA et al. 09/04/1984 YAMAZAKI.S 4,470,060 4,500,388 02/19/1985 OHMURA et al. TAMURA et al. 4,565,584 01/21/1986 04/08/1986 YAMAZAKI.S 4,581,476 4,581,620 04/08/1986 YAMAZAKI/et al. 04/22/1986 4,584,025 TAKAOKA et al. 4,591,892 05/27/1986 YAMAZAKI.S 07/01/1986 IPR/A 4,597,160 Ü MALHI.S 4,621,276 12/04/1986 VASUDEV.P 4,659,392 04/21/1987 4,680,580 07/14/198/7 KAWAHARA.Y 4,690,717 09/01/1/987 YAMAZAKI.S 4,693,759 NOGUCHI et al. 09/1/5/1987 4,729,009 08/01/1988 ANG.S 4,740,829 NAKAGIRI et al. 04/26/1988 4,743,567 05/10/1988 PANDYA et al. 4,755,865 07/05/1988 WILSON et al. 4,760,008 07/26/1988 YAMAZAKI et al. 4,766,477 08/23/1988 NAKAGAWA et al. 09/20/1988 RYUICHI et al. 4,772,927 4,795,6/79 01/03/1989 RAMESH et al. 4,814,842 03/21/1989 NAKAGAWA et al. 4,81/8,077 04/04/1989 OHWADA et al. Examiner Date Considered \*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this formwith next communication to applicant.

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Form PTO-1449 partment of Commerce Atty Docket 0756-209 Serial No. 09/499,619 (Rev. 8-83) and Trademark Office Applicants: Shunpei YAMAZAKI MATION DISCLOSURE STATEMENT Filing Date: February 07, 2000 Group Art Unit: 2815 **FOREIGN PATENT DOCUMENTS Document Number** Date Country Class Subclass Translation Initial Νo **Pull Ena** 55-032026 03/06/1980 JP Full Eng 55-050663 04/12/1980 JP Full Eng 04/12/1980 55-050664 JP Full Eng 06/21/1980 JP 55-082458 06/21/1982 Eng Abst 57-099729 JP Full Eng 02/18/1983 JP 58-027364 Full Eng 02/18/1993 JP 58-027365 Full Eng 06/01/1983 58-092217 JP 09/16/1983 JP Full Eng 58-155773 Full Eng 09/16/1983 58-155774 JP Full Eng 09/24/1983 JP 58-161380 Eng Abst 58-182816 10/25/1983 JP Full Eng 02/27/1984 JP 59-035423 Full Eng 02/27/1984 JP 59-035488 Full Eng 04/24/1984 59-072128 JP, 04/24/1984 ĴΡ Full Eng 59-072182 Full Eng 59-115574 07/04/1984 JP Full Eng 12/04/1/985 JP 60-245172 Full Eng 12/04/1985 JP 60-245173 **1**2/04/1985 Full Eng JP 60-245174 Eng Abst 01/09/1986 JP 61-004021 Eng Abst 61-126595 06/14/1986 JP Eng Abst 61-136262 06/24/1986 JP Full Eng 06/28/1986 JΡ 61-141174 Eng Abst 62-115748 05/27/1987 JP Eng Abst 62-126677 06/08/1987 JP Eng Abst 62-160425 07/16/1987 JP Eng Abst **£**3-096636 04/27/1988 JP Eng Abst 05/02/1988 JP 63-100777 Eng Abst 09/12/1988 JP 63-219172 Eng Abst 63-237570 10/04/1988 JP Date Considered Examiner \*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if

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